



YOUSHANG SEMICONDUCTOR

设计研发新型功率器件

各类小信号开关

中低压及高压大电流等场效应管

0755-83047638

ysbdt@szyoushang.cn

www.szyoushang.cn



企业微信二维码



企业QQ二维码

Product Summary

Device	$V_{(BR)DSS}$	$R_{DS(ON)}$ max	Package	I_D max $T_A = +25^\circ\text{C}$
Q1	30V	55m Ω @ $V_{GS} = 10\text{V}$	TSOT26	3.8A
		65m Ω @ $V_{GS} = 4.5\text{V}$	TSOT26	3.6A
Q2	-30V	110m Ω @ $V_{GS} = -10\text{V}$	TSOT26	-2.5A
		142m Ω @ $V_{GS} = -4.5\text{V}$	TSOT26	-2.1A

Features

- Complementary MOSFET
- Low On-Resistance
- Low Input Capacitance
- Fast Switching Speed

Description

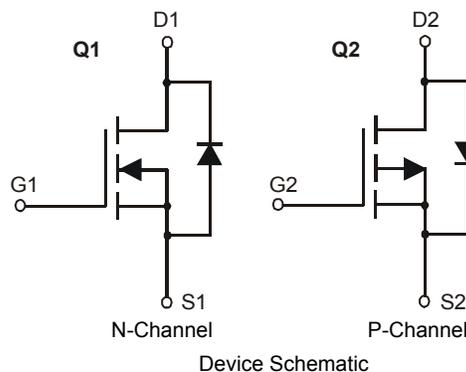
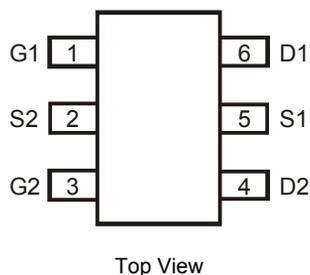
This MOSFET has been designed to minimize the on-state resistance ($R_{DS(ON)}$) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

Applications

- Backlighting
- Power Management Functions
- DC-DC Converters

Mechanical Data

- Case: TSOT26
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections Indicator: See diagram
- Terminals: Finish — NiPdAu over Copper Leadframe. Solderable per MIL-STD-202, Method 208 (e4)
- Weight: 0.008 grams (approximate)



Maximum Ratings - Q1 and Q2 (@ $T_A = +25^\circ\text{C}$, unless otherwise specified.)

Characteristic	Symbol	Q1	Q2	Units	
Drain-Source Voltage	V_{DSS}	30	-30	V	
Gate-Source Voltage	V_{GSS}	± 12	± 12	V	
Continuous Drain Current (Note 6) $V_{GS} = 10\text{V}$	Steady State $T_A = +25^\circ\text{C}$ $T_A = +70^\circ\text{C}$	I_D	3.8	-2.5	A
		I_D	3.0	-2	
	t<10s $T_A = +25^\circ\text{C}$ $T_A = +70^\circ\text{C}$	I_D	4.5	-3	A
		I_D	3.4	-2.3	
Maximum Body Diode Forward Current (Note 6)	I_S	1.5	-1.5	A	
Pulsed Drain Current (Note 6)	I_{DM}	20	-15	A	

Thermal Characteristics (@ $T_A = +25^\circ\text{C}$, unless otherwise specified.)

Characteristic	Symbol	Value	Units	
Total Power Dissipation (Note 5)	P_D	$T_A = +25^\circ\text{C}$	0.85	W
		$T_A = +70^\circ\text{C}$	0.54	
Thermal Resistance, Junction to Ambient (Note 5)	$R_{\theta JA}$	Steady state	147	$^\circ\text{C/W}$
		t<10s	103	
Total Power Dissipation (Note 6)	P_D	$T_A = +25^\circ\text{C}$	1.3	W
		$T_A = +70^\circ\text{C}$	0.83	
Thermal Resistance, Junction to Ambient (Note 6)	$R_{\theta JA}$	Steady state	96	$^\circ\text{C/W}$
		t<10s	67	
Thermal Resistance, Junction to Case (Note 6)	$R_{\theta JC}$	36	$^\circ\text{C/W}$	
Operating and Storage Temperature Range	T_J, T_{STG}	-55 to +150	$^\circ\text{C}$	

Electrical Characteristics - Q1 (@ $T_A = +25^\circ\text{C}$, unless otherwise specified.)

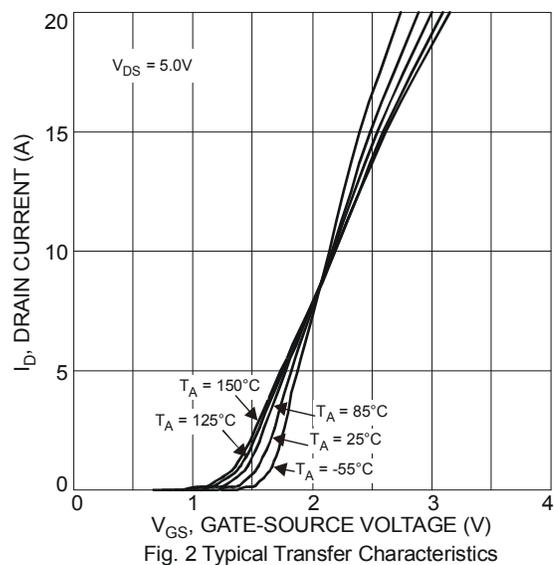
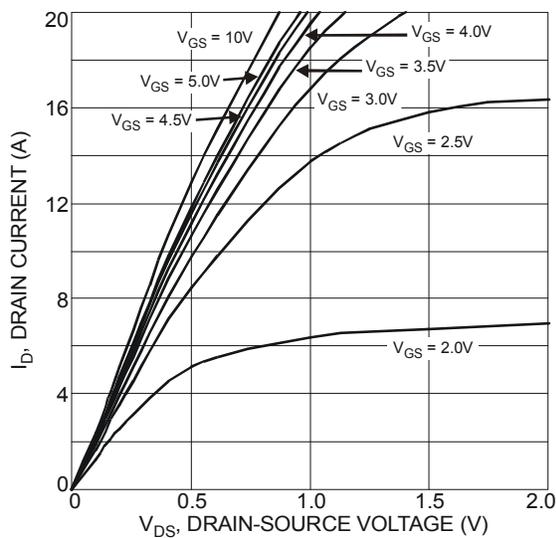
Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 7)						
Drain-Source Breakdown Voltage	BV_{DSS}	30	-	-	V	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$
Zero Gate Voltage Drain Current @ $T_J = +25^\circ\text{C}$	I_{DSS}	-	-	1	μA	$V_{DS} = 30\text{V}, V_{GS} = 0\text{V}$
Gate-Source Leakage	I_{GSS}	-	-	± 100	nA	$V_{GS} = \pm 12\text{V}, V_{DS} = 0\text{V}$
ON CHARACTERISTICS (Note 7)						
Gate Threshold Voltage	$V_{GS(th)}$	0.5	1	1.5	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
Static Drain-Source On-Resistance	$R_{DS(on)}$	-	34	55	m Ω	$V_{GS} = 10\text{V}, I_D = 3.4\text{A}$
		-	38	65		$V_{GS} = 4.5\text{V}, I_D = 3\text{A}$
		-	49	85		$V_{GS} = 2.5\text{V}, I_D = 2\text{A}$
Forward Transfer Admittance	$ Y_{fs} $	-	6	-	S	$V_{DS} = 5\text{V}, I_D = 3.4\text{A}$
Diode Forward Voltage (Note 7)	V_{SD}	-	0.75	1.0	V	$V_{GS} = 0\text{V}, I_S = 1\text{A}$
DYNAMIC CHARACTERISTICS (Note 8)						
Input Capacitance	C_{iss}	-	422	-	pF	$V_{DS} = 15\text{V}, V_{GS} = 0\text{V}, f = 1.0\text{MHz}$
Output Capacitance	C_{oss}	-	41	-	pF	
Reverse Transfer Capacitance	C_{rss}	-	39	-	pF	
Gate resistance	R_g	-	1.26	-	Ω	$V_{DS} = 0\text{V}, V_{GS} = 0\text{V}, f = 1.0\text{MHz}$
Total Gate Charge ($V_{GS} = 4.5\text{V}$)	Q_g	-	5.4	-	nC	$V_{GS} = 10\text{V}, V_{DS} = 15\text{V}, I_D = 3.1\text{A}$
Total Gate Charge ($V_{GS} = 10\text{V}$)	Q_g	-	12.3	-	nC	
Gate-Source Charge	Q_{gs}	-	0.8	-	nC	
Gate-Drain Charge	Q_{gd}	-	1.2	-	nC	
Turn-On Delay Time	$t_{D(on)}$	-	1.6	-	ns	$V_{DS} = 15\text{V}, V_{GS} = 10\text{V}, R_L = 4.7\Omega, R_G = 3\Omega,$
Turn-On Rise Time	t_r	-	7.4	-	ns	
Turn-Off Delay Time	$t_{D(off)}$	-	31.2	-	ns	
Turn-Off Fall Time	t_f	-	15.6	-	ns	

- Notes:
- Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout
 - Device mounted on FR-4 substrate PC board, 2oz copper, with thermal vias to bottom layer 1inch square copper plate
 - Short duration pulse test used to minimize self-heating effect.
 - Guaranteed by design. Not subject to product testing.

Electrical Characteristics - Q2 (@ $T_A = +25^\circ\text{C}$, unless otherwise specified.)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 7)						
Drain-Source Breakdown Voltage	BV_{DSS}	-30	-	-	V	$V_{GS} = 0V, I_D = -250\mu A$
Zero Gate Voltage Drain Current @ $T_J = +25^\circ\text{C}$	I_{DSS}	-	-	-1	μA	$V_{DS} = -30V, V_{GS} = 0V$
Gate-Source Leakage	I_{GSS}	-	-	± 100	nA	$V_{GS} = \pm 12V, V_{DS} = 0V$
ON CHARACTERISTICS (Note 7)						
Gate Threshold Voltage	$V_{GS(th)}$	-0.4	-0.8	-1.2	V	$V_{DS} = V_{GS}, I_D = -250\mu A$
Static Drain-Source On-Resistance	$R_{DS(on)}$	-	70	110	m Ω	$V_{GS} = -10V, I_D = -2.3A$
		-	81	142		$V_{GS} = -4.5V, I_D = -2A$
		-	105	190		$V_{GS} = -2.5V, I_D = -1A$
		-	-	-		$V_{GS} = -10V, I_D = -2.3A$
Forward Transfer Admittance	$ Y_{fs} $	-	5.3	-	S	$V_{DS} = -5V, I_D = -2.3A$
Diode Forward Voltage (Note 7)	V_{SD}	-	-0.8	-1.0	V	$V_{GS} = 0V, I_S = -1A$
DYNAMIC CHARACTERISTICS (Note 8)						
Input Capacitance	C_{iss}	-	541	-	pF	$V_{DS} = -15V, V_{GS} = 0V,$ $f = 1.0\text{MHz}$
Output Capacitance	C_{oss}	-	46	-	pF	
Reverse Transfer Capacitance	C_{rss}	-	43	-	pF	
Gate resistance	R_g	-	16.9	-	Ω	$V_{DS} = 0V, V_{GS} = 0V, f = 1.0\text{MHz}$
Total Gate Charge ($V_{GS} = -4.5V$)	Q_g	-	6.5	-	nC	$V_{GS} = -10V, V_{DS} = -15V,$ $I_D = -2.3A$
Total Gate Charge ($V_{GS} = -10V$)	Q_g	-	13.8	-	nC	
Gate-Source Charge	Q_{gs}	-	1.0	-	nC	
Gate-Drain Charge	Q_{gd}	-	1.6	-	nC	
Turn-On Delay Time	$t_{D(on)}$	-	1.7	-	ns	$V_{DS} = -15V, V_{GS} = -10V,$ $R_L = 6\Omega, R_G = 3\Omega,$
Turn-On Rise Time	t_r	-	4.6	-	ns	
Turn-Off Delay Time	$t_{D(off)}$	-	18.3	-	ns	
Turn-Off Fall Time	t_f	-	2.2	-	ns	

Notes: 7. Short duration pulse test used to minimize self-heating effect.
 8. Guaranteed by design. Not subject to product testing.

N Channel - Q1


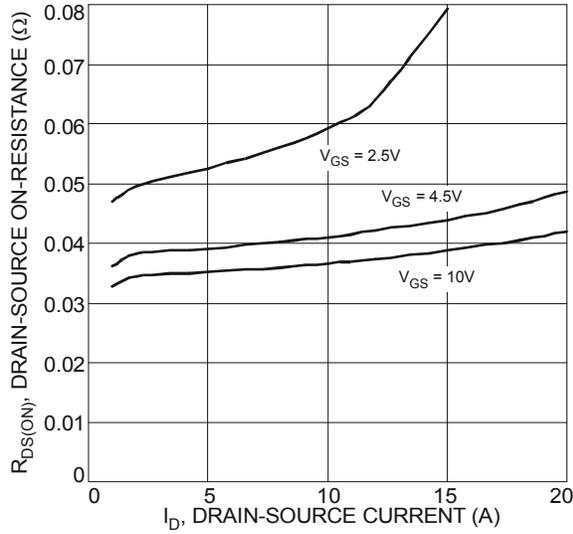


Fig. 3 Typical On-Resistance vs. Drain Current and Gate Voltage

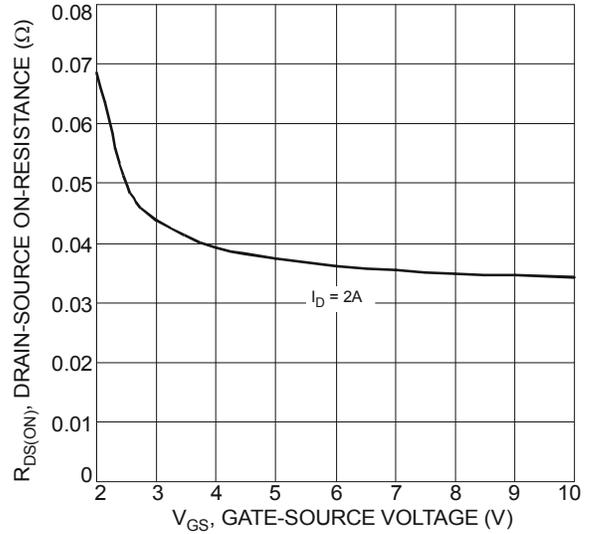


Fig. 4 Typical Drain-Source On-Resistance vs. Gate-Source Voltage

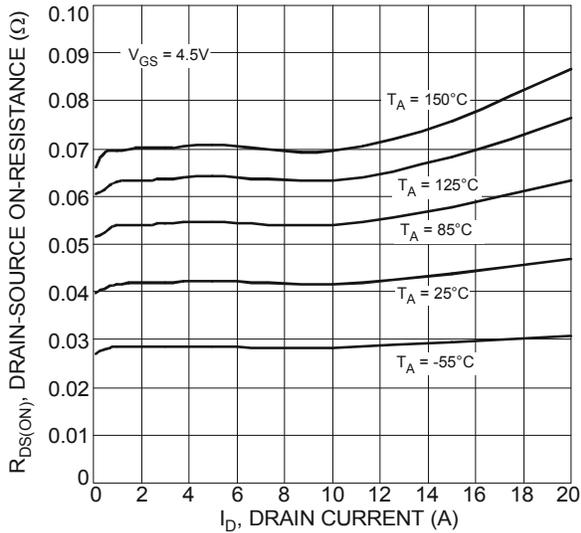


Fig. 5 Typical On-Resistance vs. Drain Current and Temperature

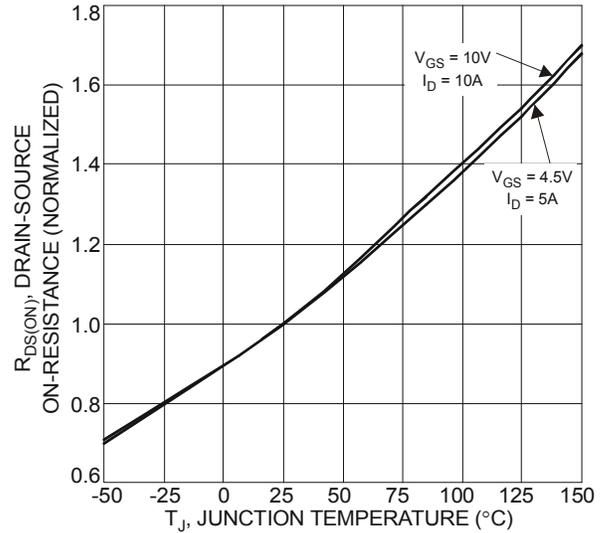


Fig. 6 On-Resistance Variation with Temperature

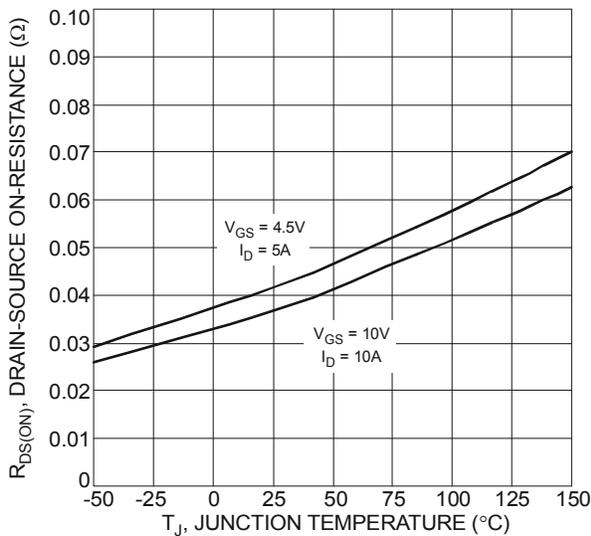


Fig. 7 On-Resistance Variation with Temperature

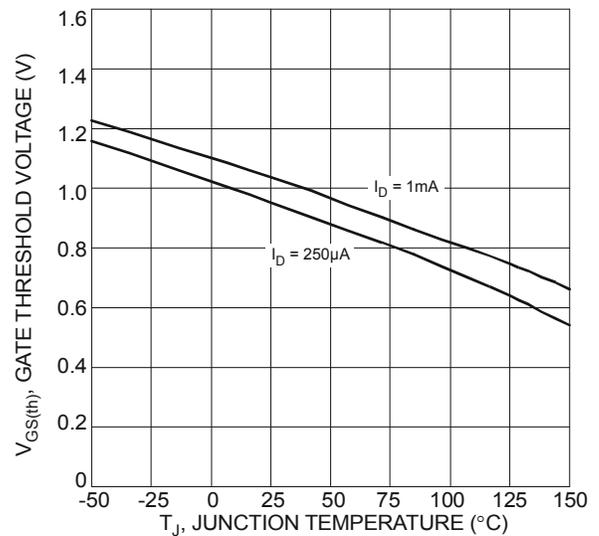


Fig. 8 Gate Threshold Variation vs. Ambient Temperature

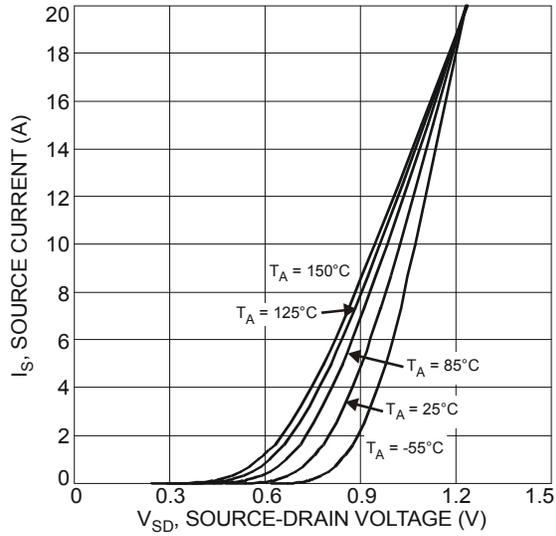


Fig. 9 Diode Forward Voltage vs. Current

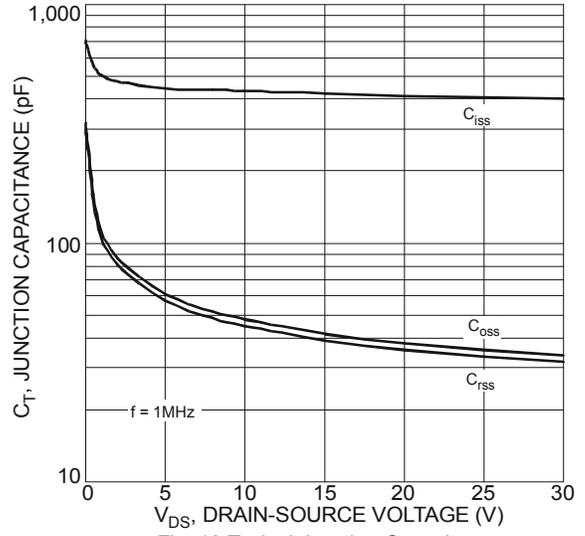


Fig. 10 Typical Junction Capacitance

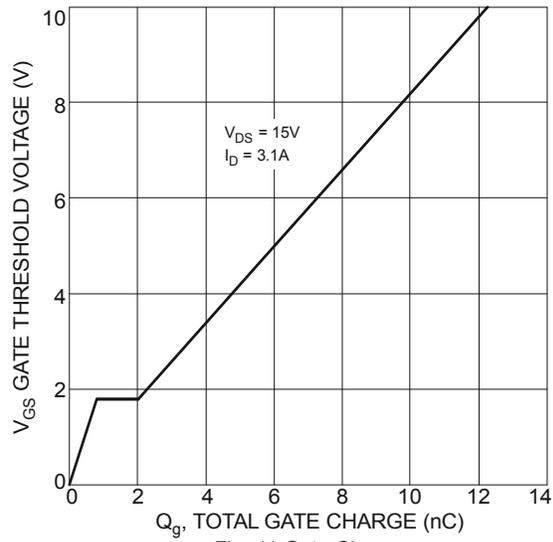


Fig. 11 Gate Charge

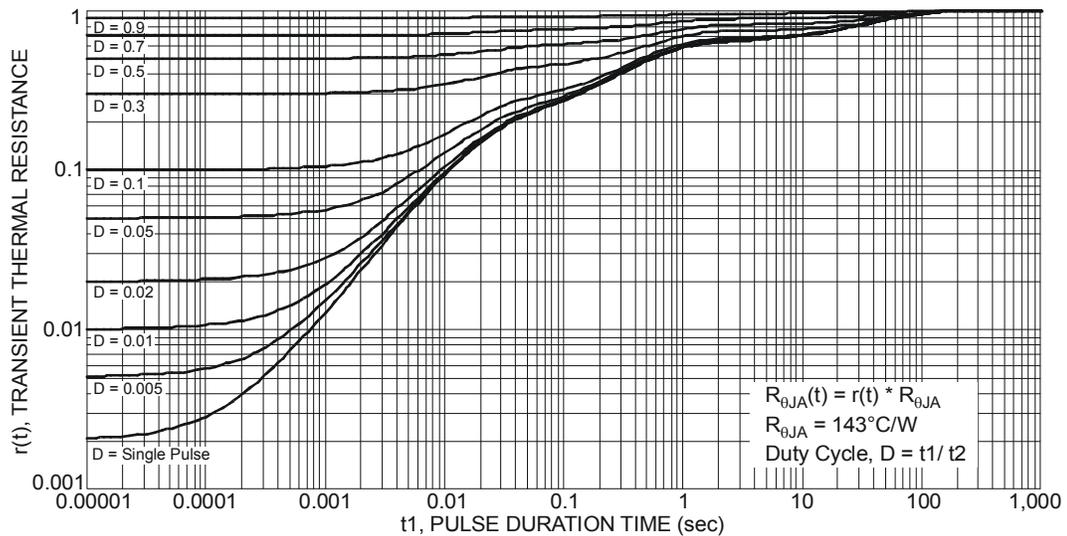
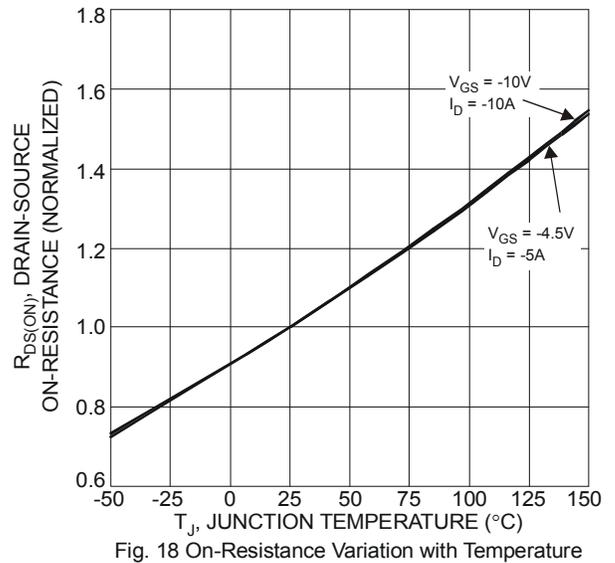
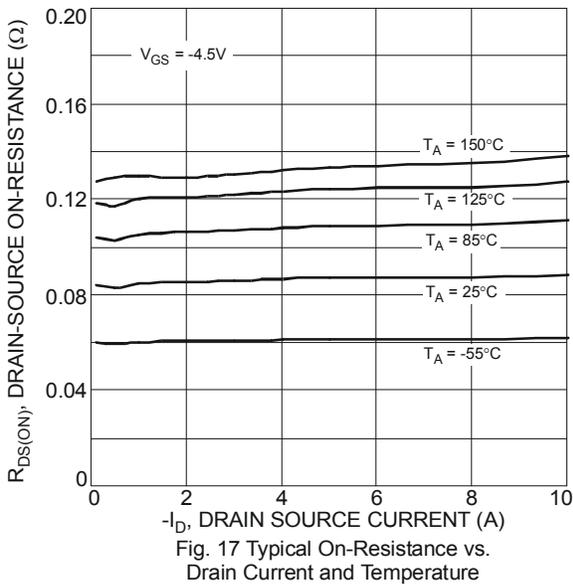
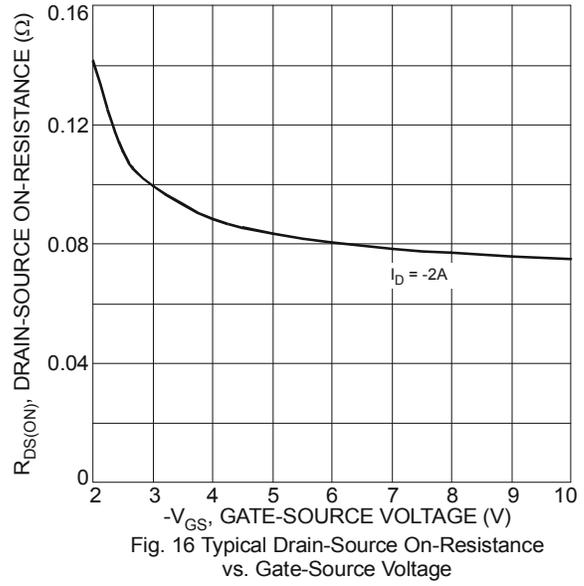
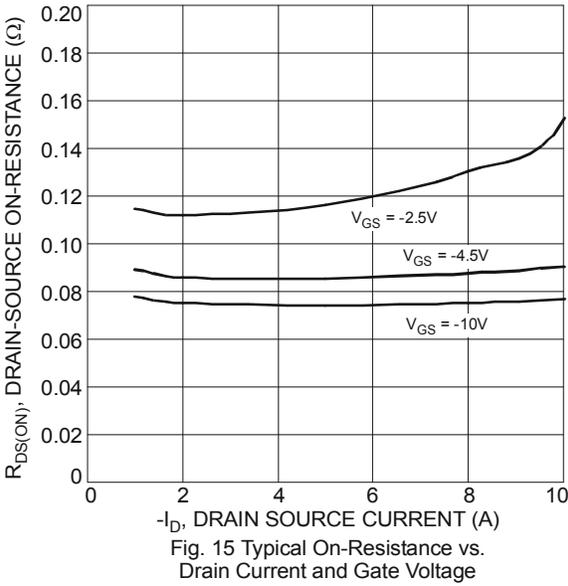
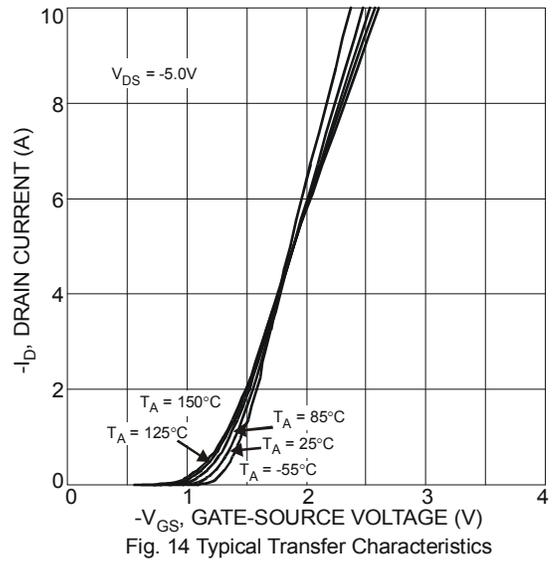
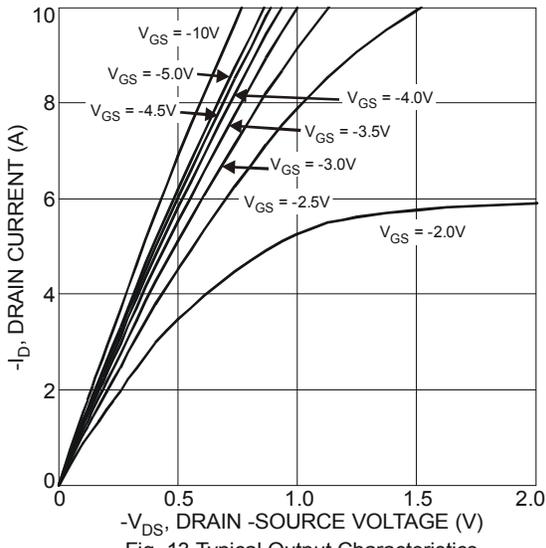


Fig. 12 Transient Thermal Resistance

P Channel - Q2



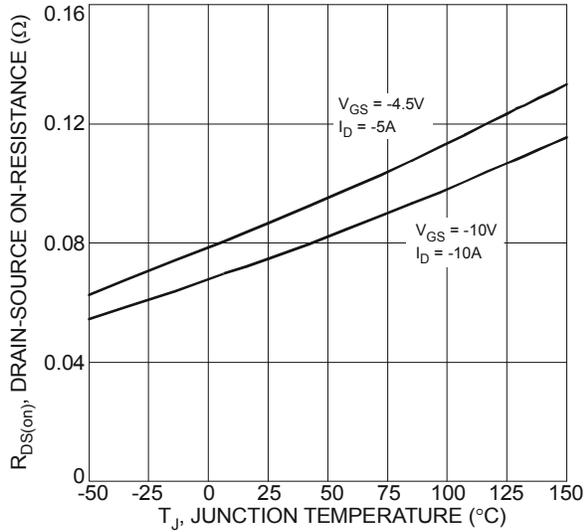


Fig. 19 On-Resistance Variation with Temperature

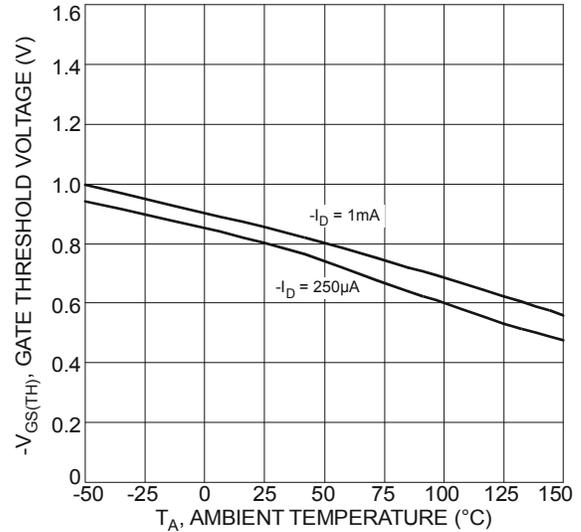


Fig. 20 Gate Threshold Variation vs. Ambient Temperature

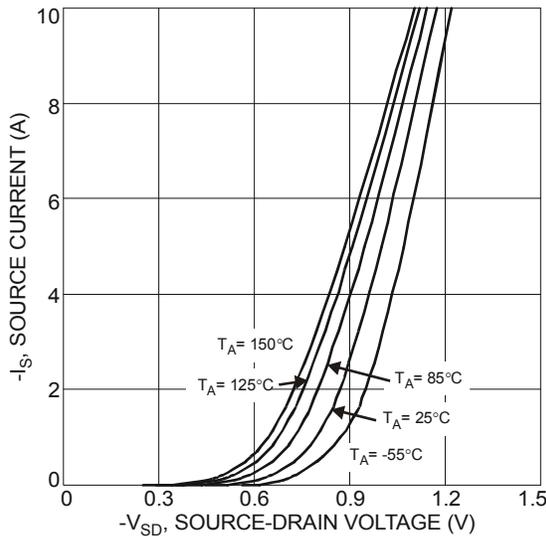


Fig. 21 Diode Forward Voltage vs. Current

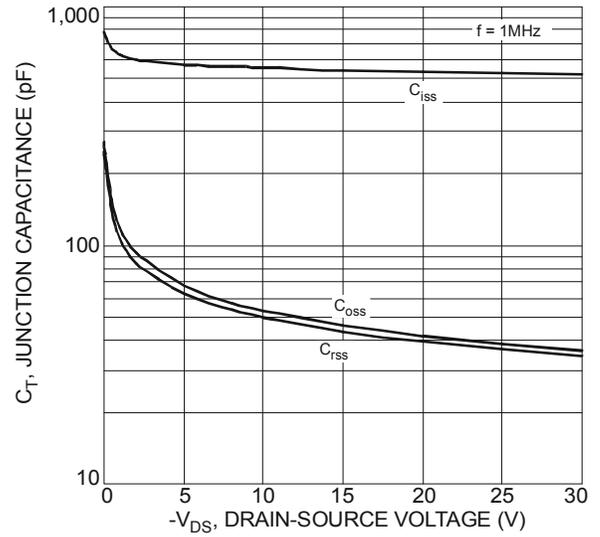


Fig. 22 Typical Junction Capacitance

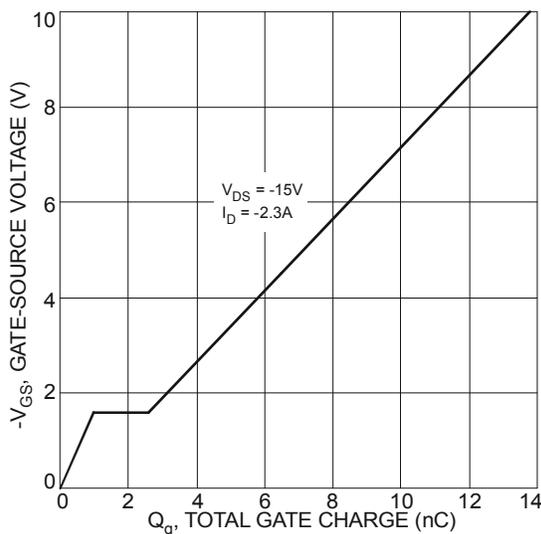
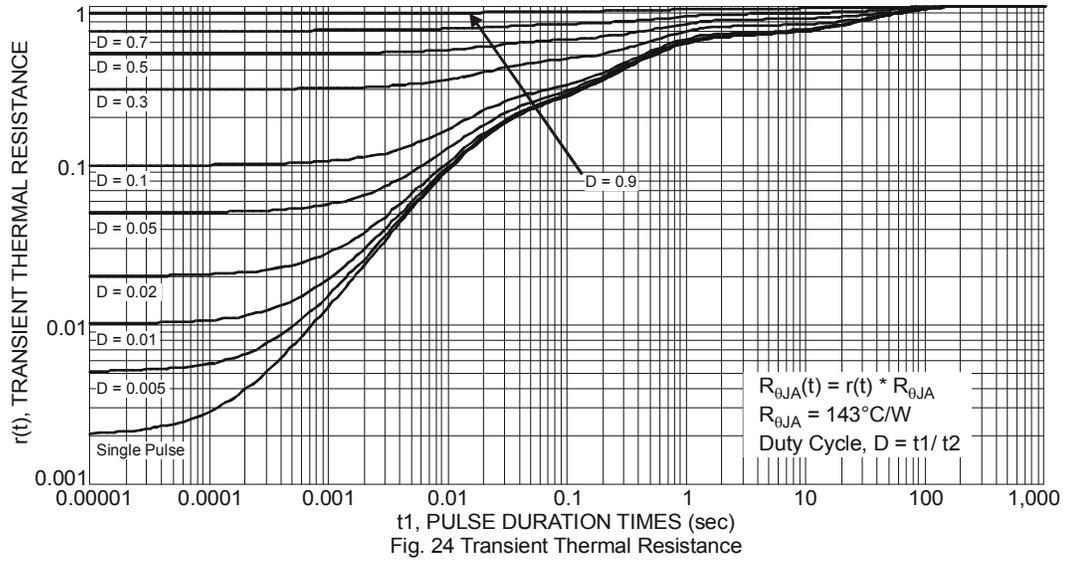
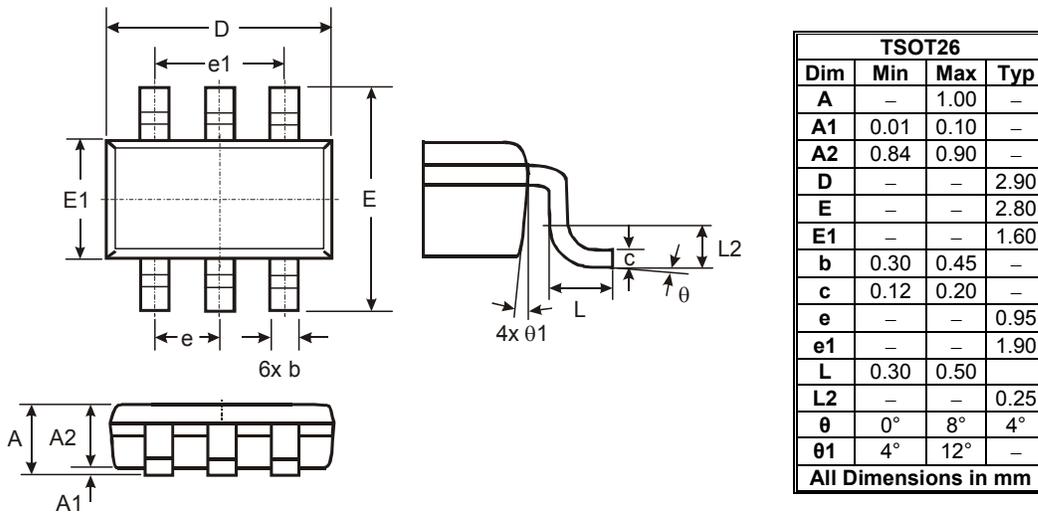


Fig. 23 Gate-Charge Characteristics



Package Outline Dimensions



Suggested Pad Layout

